

**Search Notes**

Application No.

10/044,799

Examiner

Granvill D Lee, Jr

Applicant(s)

SEO ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
438	364,99	4/16/2003	gl
438	184,257	4/16/2003	GL
438	229-230	4/16/2003	GL
438	299,725	4/16/2003	GL
257	900	4/16/2003	GL
257	314-315	4/16/2003	GL
add.438	595,666	4/28/2004	GL
	696,723	4/28/2004	GL
	734	4/28/2004	GL
above	updated	10/15/2004	GL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
438	184,299	10/15/2004	GL
438	229-230	10/15/2004	GL
438	364,595	10/15/2004	GL
257/900		10/15/2004	GR

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
sac/self-aligned spacer,etch-stop,gate stack,spacer/lower/higher,hard mask,gate electrode	4/16/2003	GL
above up-dated	4/28/2003	GL
above up-dated	10/15/2004	GL